November 2002



ISL9K1560G3

15A, 600V Stealth™ Dual Diode

General Description

The ISL9K1560G3 is a StealthTM dual diode optimized for low loss performance in high frequency hard switched applications. The StealthTM family exhibits low reverse recovery current ($I_{RM(REC)}$) and exceptionally soft recovery under typical operating conditions.

This device is intended for use as a free wheeling or boost diode in power supplies and other power switching applications. The low $I_{RM(REC)}$ and short t_a phase reduce loss in switching transistors. The soft recovery minimizes ringing, expanding the range of conditions under which the diode may be operated without the use of additional snubber circuitry. Consider using the Stealth $^{\rm TM}$ diode with an SMPS IGBT to provide the most efficient and highest power density design at lower cost.

Formerly developmental type TA49410.

Features

•	Soft Recovery $t_b/t_a > 1.2$
•	Fast Recovery t_{rr} < 30ns
•	Operating Temperature 175°C
•	Reverse Voltage

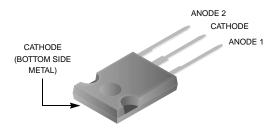
Avalanche Energy Rated

Applications

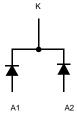
- Switch Mode Power Supplies
- · Hard Switched PFC Boost Diode
- · UPS Free Wheeling Diode
- · Motor Drive FWD
- SMPS FWD
- · Snubber Diode

Package

JEDEC STYLE TO-247



Symbol

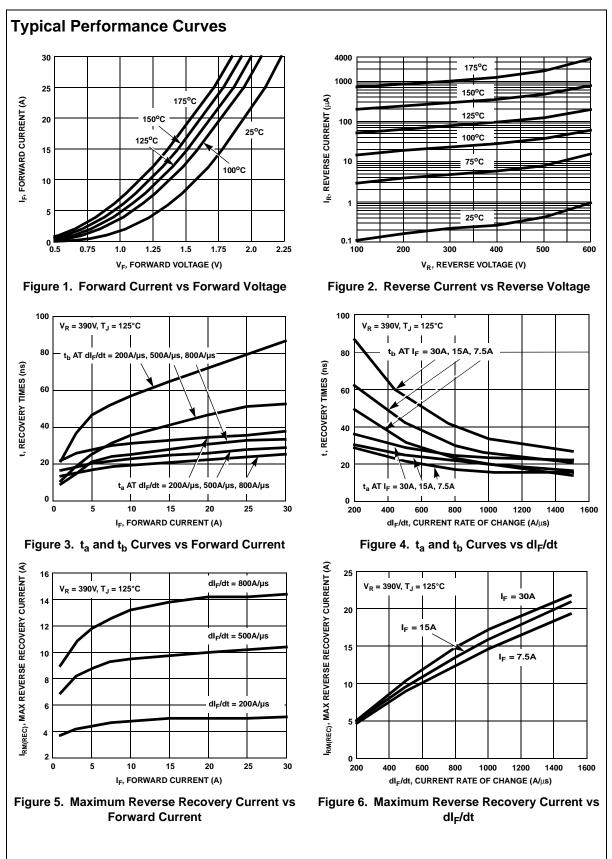


Device Maximum Ratings (per leg) T_C = 25°C unless otherwise noted

Symbol	Parameter	Ratings	Units
V _{RRM}	Repetitive Peak Reverse Voltage	600	V
V _{RWM}	Working Peak Reverse Voltage	600	V
V _R	DC Blocking Voltage	600	V
I _{F(AV)}	Average Rectified Forward Current (T _C = 145°C) Total Device Current (Both Legs)	15 30	A A
I _{FRM}	Repetitive Peak Surge Current (20kHz Square Wave)	30	Α
I _{FSM}	Nonrepetitive Peak Surge Current (Halfwave 1 Phase 60Hz)	200	Α
P _D	Power Dissipation	150	W
E _{AVL}	Avalanche Energy (1A, 40mH)	20	mJ
T _J , T _{STG}	Operating and Storage Temperature Range	-55 to 175	°C
T _L T _{PKG}	Maximum Temperature for Soldering Leads at 0.063in (1.6mm) from Case for 10s	300	°C
7110	Package Body for 10s, See Techbrief TB334	260	°C

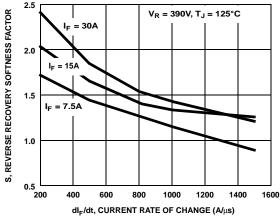
CAUTION: Stresses above those listed in "Device Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

K150	Marking	Device	Package	Tape Width			Quan	tity
	60G3	ISL9K1560G3	TO-247 N/A				30	
lectric	al Char	acteristics (per leg)	T _C = 25°C unles	s otherwise noted				
Symbol		Parameter	Test 0	Conditions	Min	Тур	Max	Unit
ff State	Characte	ristics				•		
I _R			V _R = 600V	T _C = 25°C		-	100	μΑ
'K	Instantaneous Reverse Current		VR = 000 V	$T_{\rm C} = 125^{\circ}{\rm C}$	-	-	1.0	mA
n State	Characte	eristics				•		
V _F	Instantaneous Forward Voltage		$I_F = 15A$ $T_C = 25^{\circ}C$		-	1.8	2.2	V
				T _C = 125°C	-	1.65	2.0	V
ynamic	Characte	eristics						
СЈ	Junction Ca	pacitance	$V_R = 10V, I_F = 0$	A	-	62	-	рF
!4 - 1- !	Ob		•				·	
	g Charact		I					ı
t _{rr}	Reverse Re	ecovery Time		$100A/\mu s$, $V_R = 30V$	-	25	30	ns
	D			= $100A/\mu s$, $V_R = 30V$	-	35	40	ns
t _{rr}		ecovery Time	I _F = 15A, dI _F /dt = 200A/μs		-	29.4	-	ns
RM(REC)		Reverse Recovery Current	$V_R = 390V, T_C =$		-	3.5	-	A
Q _{RR}		ecovered Charge			-	57	-	nC
t _{rr}		ecovery Time	$I_F = 15A$,		-	90	-	ns
. S	Softness Fa		dI _F /dt = 200A/μs, V _R = 390V, T _C = 125°C		-	2.0	-	_
RM(REC)		Reverse Recovery Current			-	5.0	-	A
Q _{RR}		ecovered Charge	_		-	275	-	nC
t _{rr}		ecovery Time	$I_F = 15A$,		-	52	-	ns
S	Softness Fa		$dI_F/dt = 800A/\mu s$ $V_R = 390V$,	ō,	-	1.36	-	
I _{RM(REC)}		Reverse Recovery Current	$T_{\rm C} = 125^{\circ}{\rm C}$		-	13.5	-	Α
Q _{RR}		ecovered Charge] ~		-	390	-	nC
dI _M /dt	Maximum d	li/dt during t _b			-	800	-	A/µ
hermal	Characte	ristics						
$R_{\theta JC}$	Thermal Re	esistance Junction to Case			-	-	1.0	°C/
$R_{\theta JA}$	Thermal Re	esistance Junction to Ambient	TO-247		-	-	30	°C/



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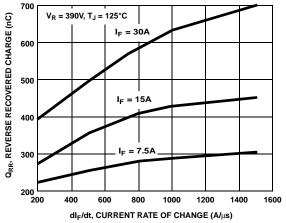
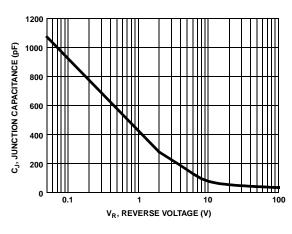


Figure 7. Reverse Recovery Softness Factor vs dI_F/dt

Figure 8. Reverse Recovered Charge vs $\mathrm{dI}_{\mathrm{F}}/\mathrm{dt}$



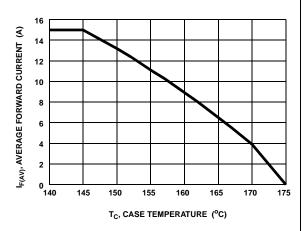


Figure 9. Junction Capacitance vs Reverse Voltage

Figure 10. DC Current Derating Curve

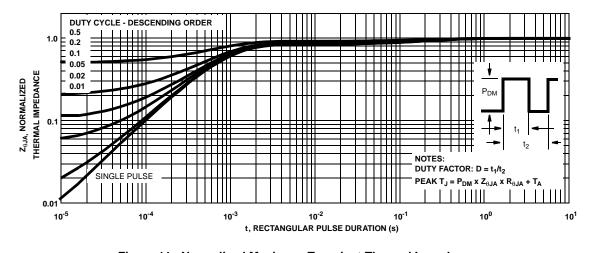
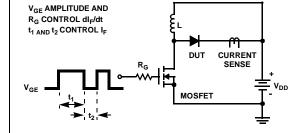


Figure 11. Normalized Maximum Transient Thermal Impedance

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Test Circuit and Waveforms



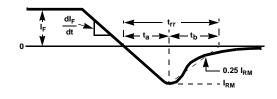
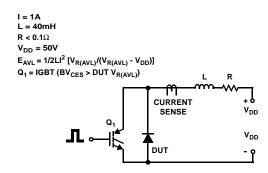


Figure 12. t_{rr} Test Circuit

Figure 13. t_{rr} Waveforms and Definitions



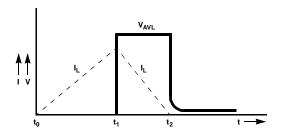


Figure 14. Avalanche Energy Test Circuit

Figure 15. Avalanche Current and Voltage Waveforms

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CROSSVOLT™ FRE	FET™	MicroPak™	QFET™	SuperSOT™-8
DOME™ Glo	obalOptoisolator™	MICROWIRE™	QS™	SyncFET™
		MSX™	QT Optoelectronics™	TinyLogic™
E ² CMOS™ HiS	SeC™	MSXPro™	Quiet Series™	TruTranslation™
EnSigna™ l²C™	ТМ	OCX™	RapidConfigure™	UHC™
Across the board. Aro	ound the world.™	OCXPro™	RapidConnect™	UltraFET [®]
The Power Franchise	TM	OPTOLOGIC®	SILENT SWITCHER®	VCX™
Programmable Active	Droop™	OPTOPLANAR™	SMART START™	

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Rev. I1